



US00D825363S

(12) **United States Design Patent** (10) **Patent No.:** **US D825,363 S**
Ave (45) **Date of Patent:** **** Aug. 14, 2018**

(54) **PATTERNING SLIT FOR SPECTROMETRY**

2017/0343413 A1* 11/2017 Ave G01J 3/04

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* cited by examiner

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(**) Term: **15 Years**

(57) **CLAIM**

(21) Appl. No.: **29/602,096**

The ornamental design for a patterning slit for spectrometry, as shown and described.

(22) Filed: **Apr. 28, 2017**

(51) **LOC (11) Cl.** **10-04**

(52) **U.S. Cl.**

USPC **D10/96**; D10/46; D10/81

(58) **Field of Classification Search**

USPC D10/46, 81, 96

CPC C23C 14/542; C23C 14/547; G01N

21/6489; G01N 21/6486; G01B 11/0683;

G01J 3/04; G01J 3/0229; G01J 3/0289;

G01J 3/0297; G01J 2003/042; G01J

2003/045; G01J 2003/047; H01L 22/12

See application file for complete search history.

DESCRIPTION

FIG. 1 is a perspective view of a patterning slit for spectrometry showing my new design;

FIG. 2 is a front and back view of a patterning slit for spectrometry showing my new design;

FIG. 3 is a side view of a patterning slit for spectrometry showing my new design;

FIG. 4 is an enlarged front and back view of a patterning slit for spectrometry showing my new design; and,

FIG. 5 is an enlarged perspective view of a patterning slit for spectrometry showing my new design.

The surrounding broken line(s) define the bounds of the claimed design and form no part thereof.

(56) **References Cited**

U.S. PATENT DOCUMENTS

2017/0003167 A1* 1/2017 Ave G01J 3/04

1 Claim, 3 Drawing Sheets

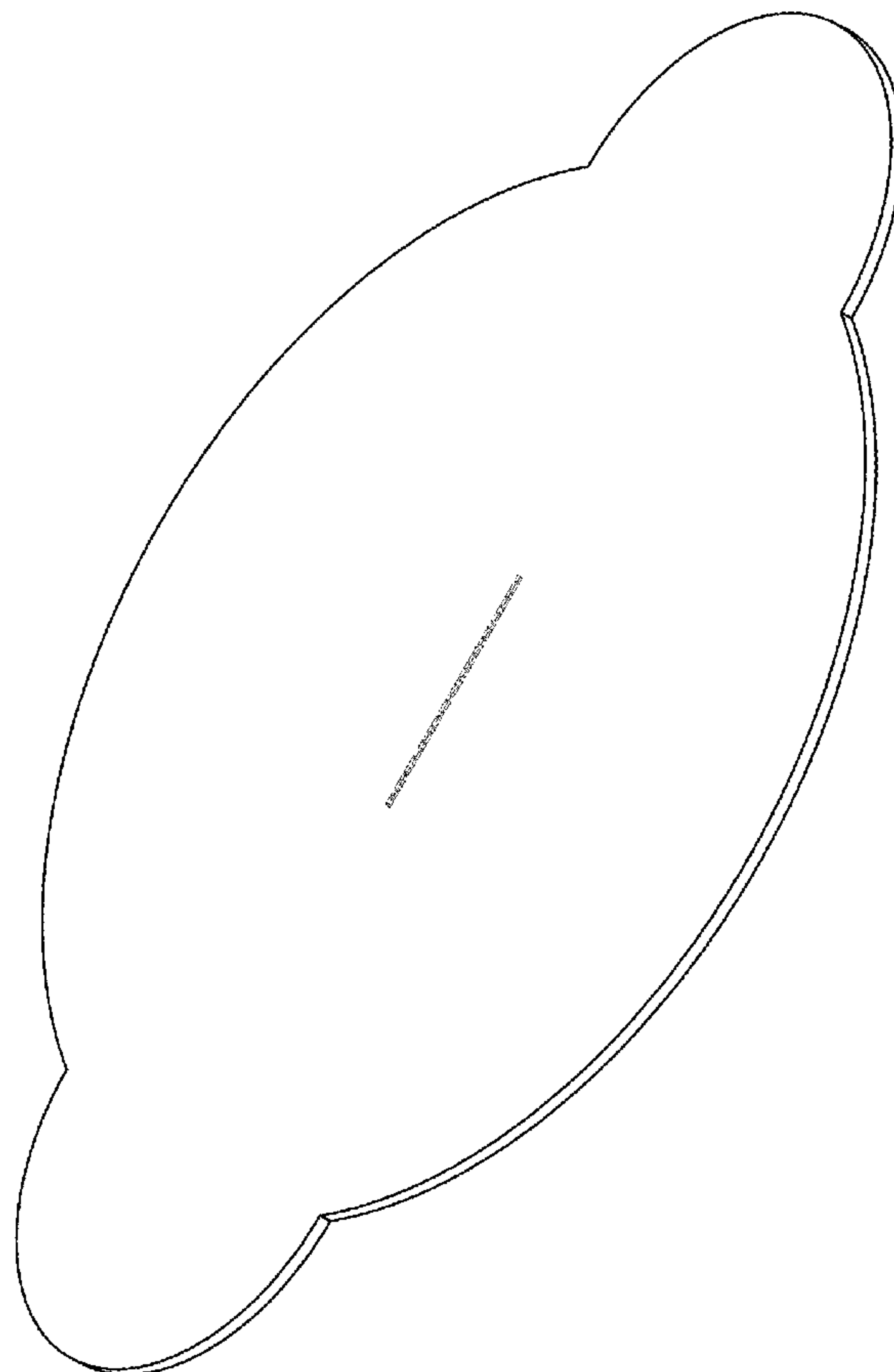


FIG 1

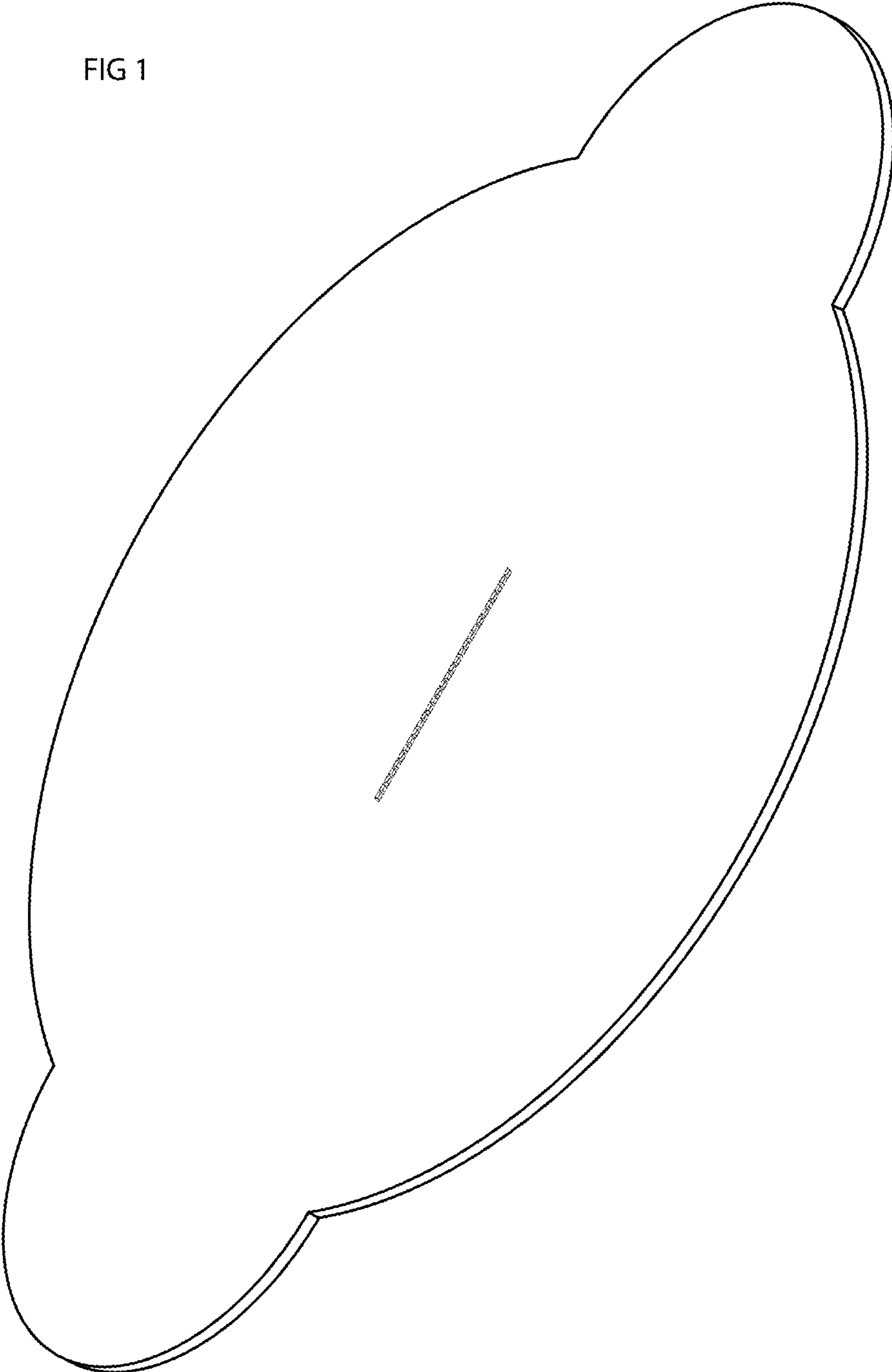


FIG 2

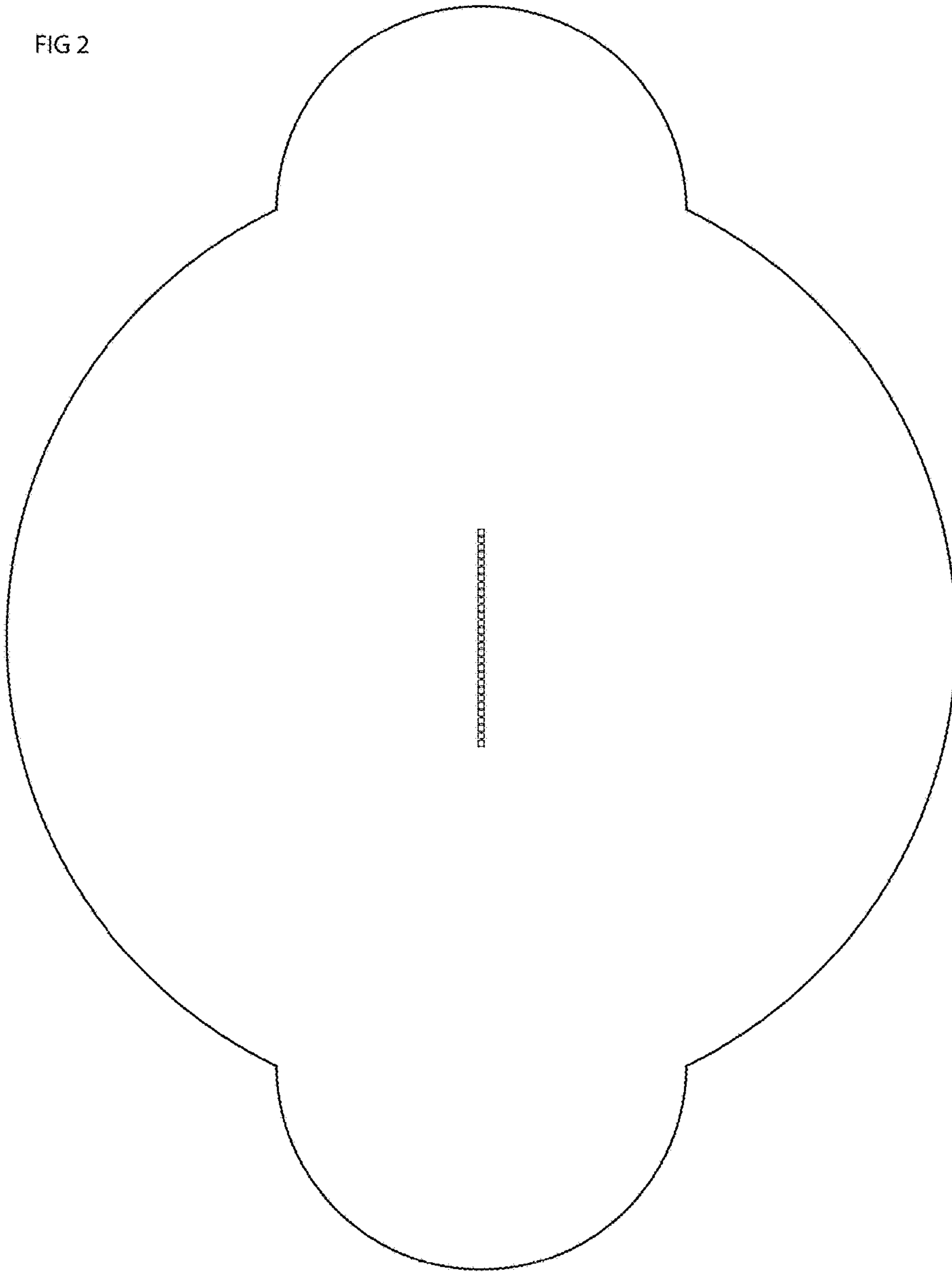


FIG 3



FIG 4

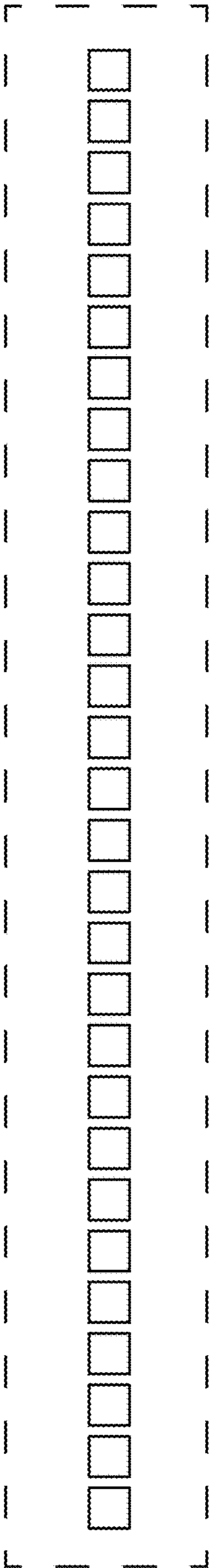


FIG 5

